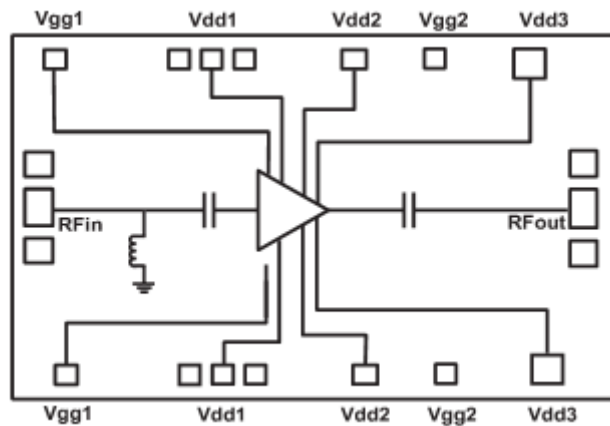


**Features**

- Frequency: 28-31GHz
- Gain: 28dB
- Psat:+ 33dBm
- Power Supply : +6.0V@700mA
- Die Size : 2.9 x 1.8 mm

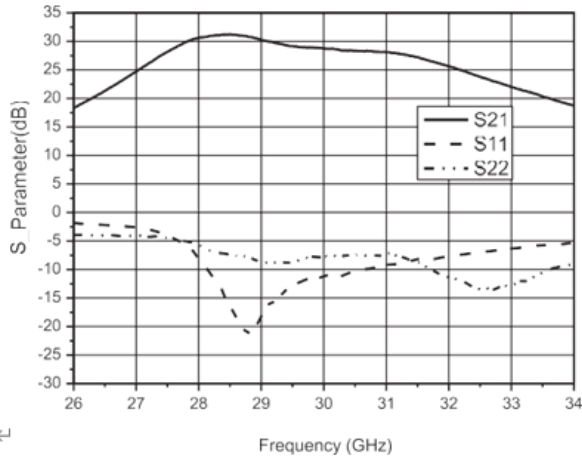
**Typical Applications**

- Test Instrumentation
- Microwave Radio & VSAT
- Military & Space
- Telecom Infrastructure
- Fiber Optics

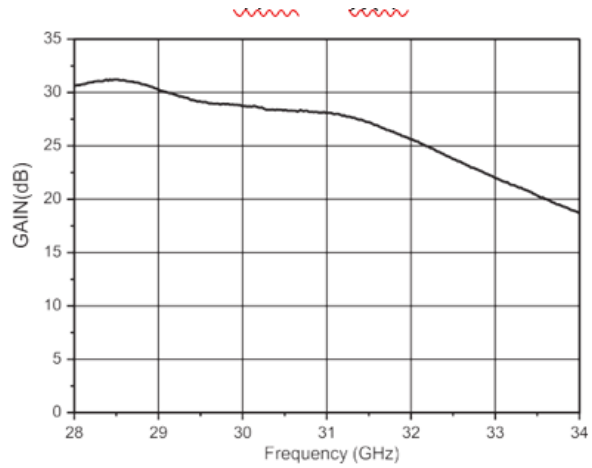
**Functional Block Diagram**

**Electrical Specifications**
**TA = +25°C, Vdd = +6V, Vgg = -0.75V (On-wafer Measurement Results)**

Parameters	Min.	Typ.	Max.	Units
<b>Frequency</b>	<b>28-31</b>			<b>GHz</b>
<b>Gain</b>		<b>28</b>		<b>dB</b>
<b>Psat</b>		<b>33</b>		<b>dBm</b>
<b>Input Return Loss</b>		<b>28</b>		<b>dB</b>
<b>Output Return Loss</b>		<b>13</b>		<b>dB</b>
<b>Operating Current</b>		<b>700</b>		<b>mA</b>

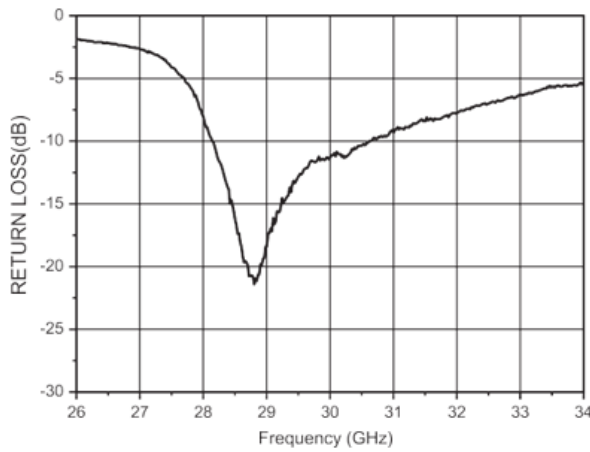
### S Parameter vs. Frequency



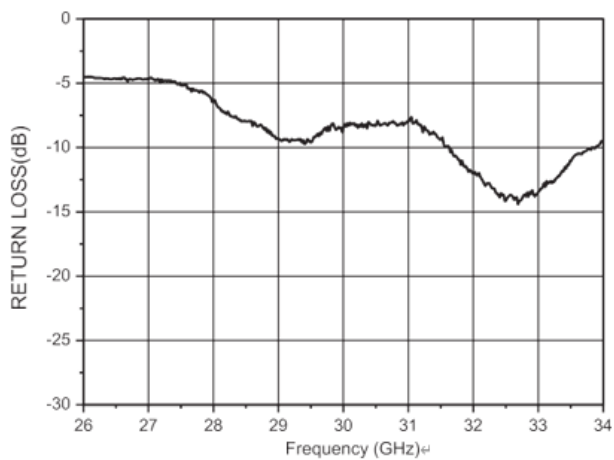
### Gain vs. Frequency



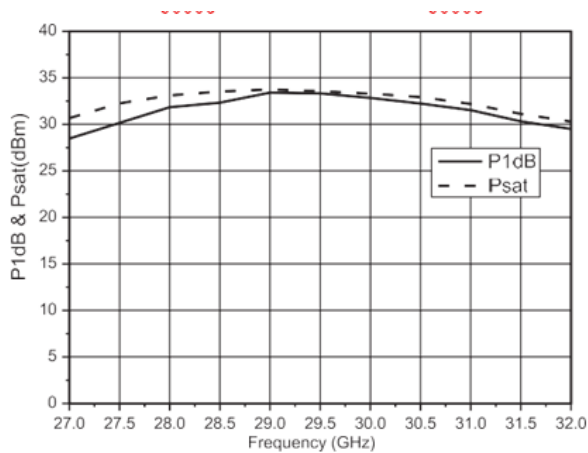
### Input Return Loss vs. Frequency



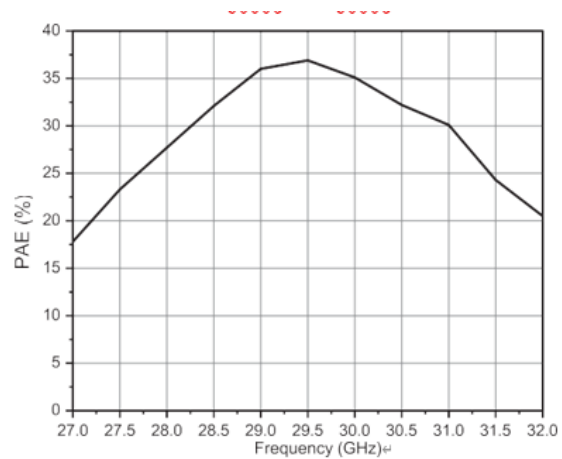
### Output Return Loss vs. Frequency



### P1dB & Psat vs. Frequency



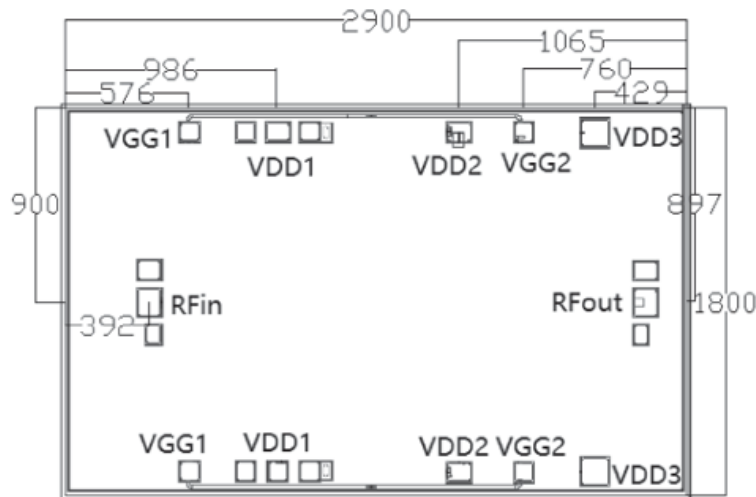
### PAE vs. Frequency





### Outline Drawing:

All Dimensions in  $\mu\text{m}$

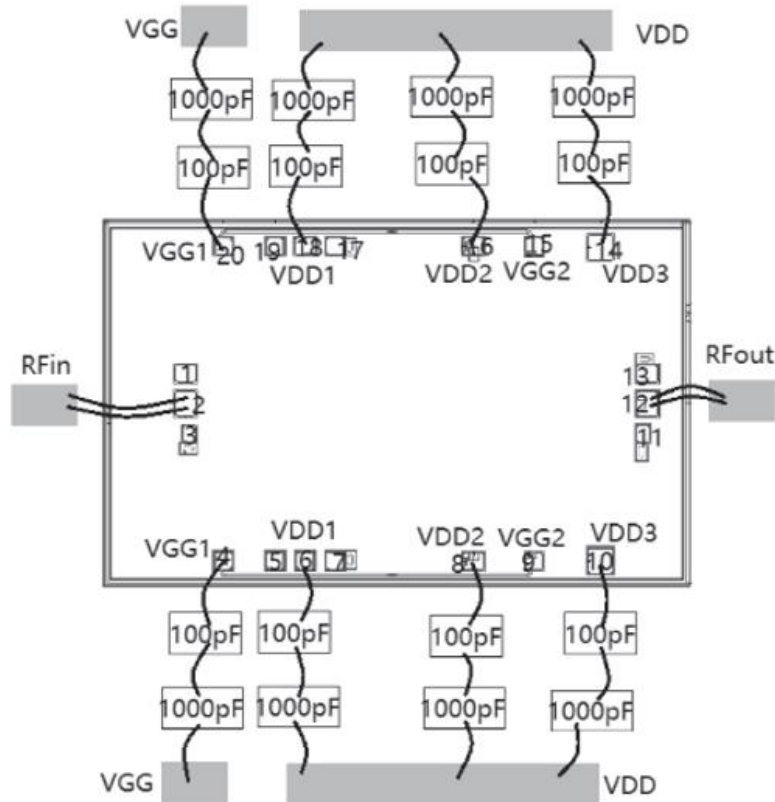


### Pad Description

Pad	Function	Description
2	RF IN	Signal input terminal, connected to 50Ω circuit.
12	RF OUT&VDD	Signal output terminal, connected to 50Ω circuit.
6,8,10,14,16,18	Vdd	Amplifier power supply, external 100pF capacitor required.
4,9,15,20	Vgg	Amplifier gate power supply, external 100pF capacitor required.
1,3,5,7,11,13,17,19	GND	Die bottom must be connected to RF/DC ground.



### Assembly Drawing (Bond testing)



#### Notes:

1. Die thickness: 100um
2. Typical bond pad is 100\*100  $\mu\text{m}^2$
3. Bond pad metalization: Gold
4. Backside metalization: Gold
5. Backside of the die (GND)
6. No connection required for unlabeled bond pads

#### Maximum Ratings:

1. Supply voltage: +6.5V
2. RF Input power: +13dBm
3. Operating temperature: -55°C to +85°C
4. Storage temperature: -65°C to +150°C